

Notice of References Cited	Application/Control No. 10/659,707	Applicant(s)/Patent Under Reexamination KANG ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0001802	01-2003	Ide et al.	345/60
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	M	US-			

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